

<b>Notice of References Cited</b>	Application/Control No. 10/593,872		Applicant(s)/Patent Under Reexamination FUJITA ET AL.	
	Examiner NATHANIEL J. LEE		Art Unit 4126	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0000622 A1	05-2001	Reeh et al.	257/98
*	B	US-6,652,972 B1	11-2003	Conzone et al.	428/426
*	C	US-2005/0006659 A1	01-2005	Ng et al.	257/099
*	D	US-2002/0171911 A1	11-2002	Maegawa, Mamoru	359/308
*	E	US-2004/0095063 A1	05-2004	Murazaki et al.	313/503
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.